

March 2013

# FCA22N60N

# N-Channel SupreMOS® MOSFET

600 V, 22 A, 165 mΩ

### **Features**

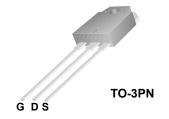
- $BV_{DSS} > 650 \text{ V } @ T_J = 150^{\circ}\text{C}$
- $R_{DS(on)}$  = 140 m $\Omega$  (Typ.)@  $V_{GS}$  = 10 V,  $I_D$  = 11 A
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 45 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss</sub>.eff = 196.4 pF)
- 100% Avalanche Tested
- · RoHS Compliant

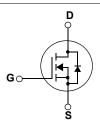
# **Application**

- PDP TV
- · Solar Inverter
- · AC-DC Power Supply

# **Description**

The SupreMOS® MOSFET is Fairchild Semiconductor®, s next-generation of high voltage super-junction (SJ) technology employing a deep trench filling process that differentiate it from the conventional MOSFETs. This advanced technology and precise process control provide lowest Rsp on-resistance, superior switching performance and ruggedness. SupreMOS MOSFET is suitable for high frequency switching power converter applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications.





# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter		FCA22N60N	Unit
V <sub>DSS</sub>	Drain to Source Voltage			600	V
V <sub>GSS</sub>	Gate to Source Voltage			±30	V
1	Drain Current	Continuous (T <sub>C</sub> = 25°C)		22	А
I <sub>D</sub>	Diam Current	Continuous (T <sub>C</sub> = 100°C)		13.8	A
I <sub>DM</sub>	Drain Current Pulsed (Note 1)		Pulsed (Note 1)		Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		672	mJ	
I <sub>AR</sub>	Avalanche Current		7.3	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy		2.75	mJ	
dv/dt	Peak Diode Recovery dv/dt	1)	Note 3)	20	V/ns
uv/ut	MOSFET dv/dt			100	V/115
D	Power Dissipation	(T <sub>C</sub> = 25°C)		205	W
$P_{D}$	Fower Dissipation	Derate above 25°C		1.64	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

### **Thermal Characteristics**

Symbol	Parameter	FCA22N60N	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.61	
$R_{\theta JS}$	Thermal Resistance, Case to Heat Sink (Typical)	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	40	

Unit

Max.

# Package Marking and Ordering Information T<sub>C</sub> = 25°C unless otherwise noted

Parameter

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCA22N60N	FCA22N60N	TO-3PN	-	-	30

**Test Conditions** 

Min.

Тур.

# **Electrical Characteristics**

Off Characteristics						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_J = 25^{\circ}\text{C}$	600	-	-	\/
	Drain to Source Breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_J = 150^{\circ}\text{C}$	650	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C	-	0.68	-	V/°C
I	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0 V	-	-	10	μА
DSS	Zero Gate Voltage Brain Gurrent	$V_{DS} = 480 \text{ V}, T_{J} = 125^{\circ}\text{C}$	-	-	100	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±50 V, V <sub>DS</sub> = 0 V	-	-	±100	nA

#### **On Characteristics**

Symbol

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	2.0	3	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 11 \text{ A}$	-	0.140	0.165	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20 \text{ V}, I_{D} = 11 \text{ A}$	-	22	1	S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 400 V V 0 V	-	1950	-	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V f = 1 MHz		75.9	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			3	-	pF
Coss	Output Capacitance	$V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	43.2	-	pF
C <sub>oss</sub> eff.	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 480 V, V <sub>GS</sub> = 0 V		196.4	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	45	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>DS</sub> = 380 V, I <sub>D</sub> = 11 A,	-	8.7	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10 V (Note 4)	-	14.5	-	nC
ESR	Equivalent Series Resistance (G-S)	Drain Open, f = 1 MHz	-	1	-	Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	16.9	-	ns
t <sub>r</sub>	Turn-On Rise Time	V <sub>DD</sub> = 380 V, I <sub>D</sub> = 11 A		-	16.7	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 4.7 \Omega$		-	49	-	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4)	-	4	-	ns

### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	22	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	66	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 11 A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 11 A	-	350	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	6	-	μС

#### Notes

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2.  $I_{AS}$  = 7.3 A,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C
- 3. I\_{SD}  $\leq$  22 A, di/dt  $\leq$  200 A/ $\mu$ s, V\_{DD}  $\leq$  380 V, Starting T\_J = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

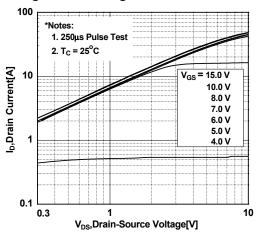


Figure 3. On-Resistance Variation vs. **Drain Current and Gate Voltage** 

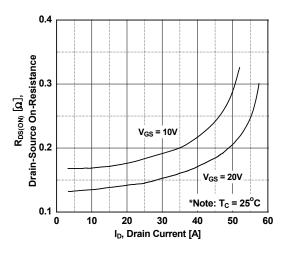


Figure 5. Capacitance Characteristics

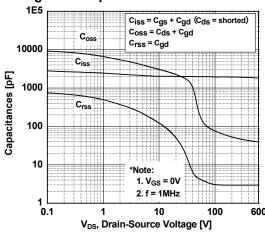


Figure 2. Transfer Characteristics

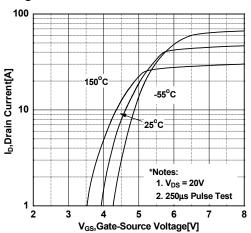


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

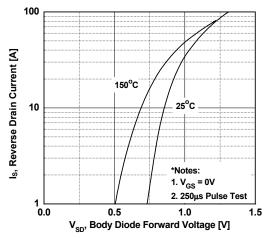
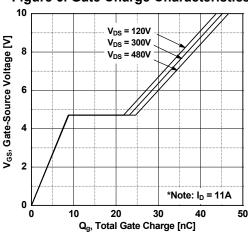
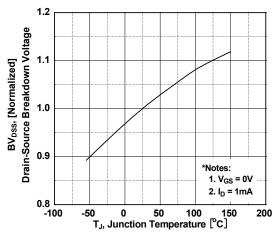


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature



vs. Temperature 3.0

Figure 8. On-Resistance Variation

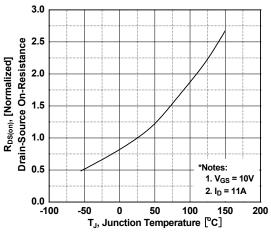


Figure 9. Maximum Safe Operating Area

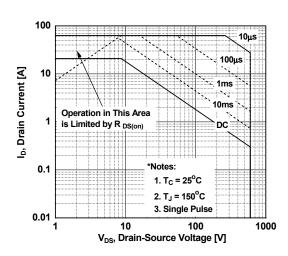


Figure 10. Maximum Drain Current vs. Case Temperature

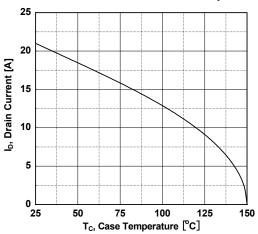
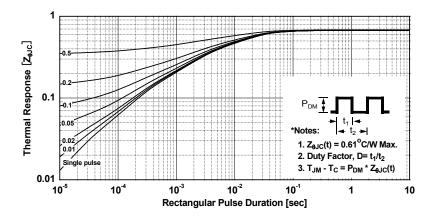
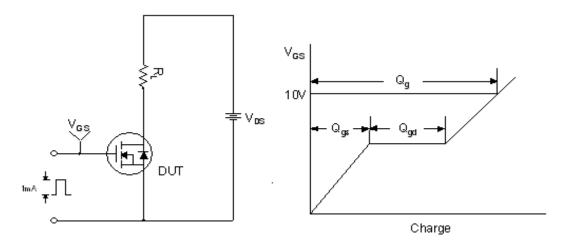


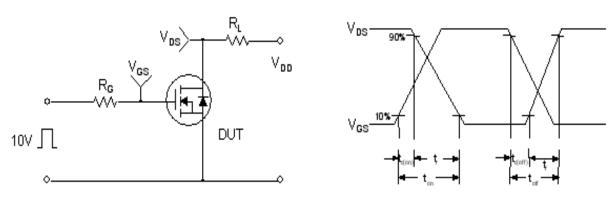
Figure 11. Transient Thermal Response Curve



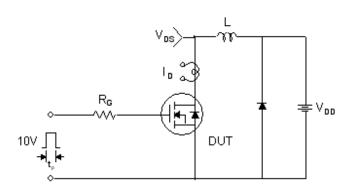
# **Gate Charge Test Circuit & Waveform**

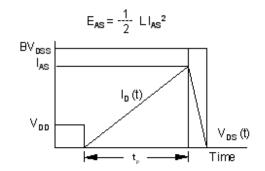


# **Resistive Switching Test Circuit & Waveforms**

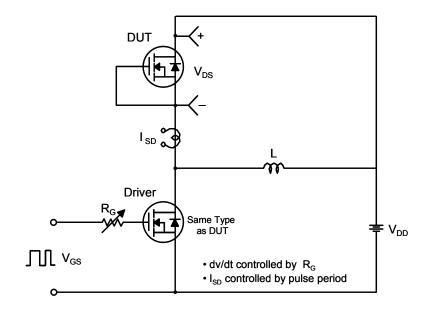


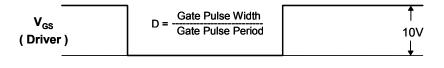
**Unclamped Inductive Switching Test Circuit & Waveforms** 

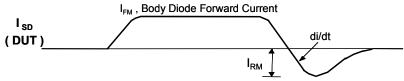




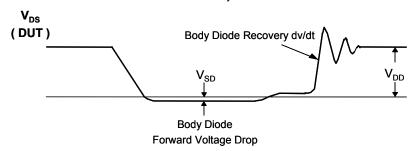
### Peak Diode Recovery dv/dt Test Circuit & Waveforms





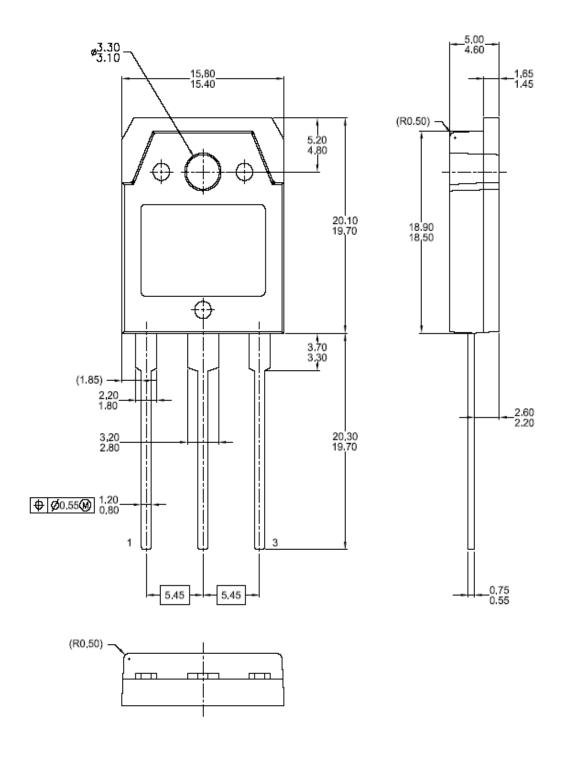


Body Diode Reverse Current



# **Mechanical Dimensions**

# TO-3PN



Dimensions in Millimeters





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